

**Search Notes**

Application/Control No.

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Examiner

Djenane M. Bayard

Applicant(s)/Patent under  
Reexamination

WANG ET AL.

Art Unit

2141

**SEARCHED**

Class	Subclass	Date	Examiner
709	227	3/17/2006	DB

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR